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| Notice of References Cited | Application/Control No. 10/614,085 | Applicant(s)/Patent Under Reexamination AWASAKA ET AL. | |
| | Examiner Sheldon J Richter | Art Unit 3748 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|-----------------------|----------------|
| * | A | US-6,684,863 | 02-2004 | Dixon et al. | 123/565 |
| * | B | US-6,651,432 | 11-2003 | Gray, Jr., Charles L. | 123/564 |
| * | C | US-6,626,164 | 09-2003 | Hitomi et al. | 123/679 |
| * | D | US-6,058,708 | 05-2000 | Heinitz et al. | 60/602 |
| * | E | US-5,345,920 | 09-1994 | Sugino et al. | 123/564 |
| * | F | US-5,307,783 | 05-1994 | Satoya et al. | 123/564 |
| * | G | US-5,297,532 | 03-1994 | Ikebe et al. | 123/564 |
| * | H | US-4,428,352 | 01-1984 | Mayer et al. | 123/564 |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|-------------------|----------------|
| * | N | JP 10266878 A | 10-1998 | Japan | TANAHASHI, TOSHIO | F02D 13/02 |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | V | |
| | W | |
| | X | |

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